

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10584717	YOON ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	PHUOC DOAN	2617

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
See Attached Seach History	6/15/2010	PHD

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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